## <sup>218</sup>U $\alpha$ decay (0.51 ms) 2005Le42,2007Le14

History

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Full Evaluation Shaofei Zhu and E. A. Mccutchan NDS 175, 1 (2021)

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Parent:  $^{218}$ U: E=0.0;  $J^{\pi}$ =0+;  $T_{1/2}$ =0.51 ms +17-10;  $Q(\alpha)$ =8775 9;  $\%\alpha$  decay=100.0

<sup>218</sup>U-Q( $\alpha$ ): from 2021Wa16.

 $^{218}\text{U-T}_{1/2}$ : from Adopted Levels of  $^{218}\text{U}$  (2019Si39).

2005Le42,2007Le14:  $^{218}$ U was produced in  $^{182}$ W( $^{40}$ Ar,4n) reaction with a beam at 186 MeV; evaporation residues (ER) were separated in-flight by the RITU gas-filled separator and implanted into PAD or DSSD silicon detectors at the focal plane. E $\alpha$  and  $T_{1/2}$  were measured by ER- $\alpha$ - $\alpha$  time and position correlations.

<sup>214</sup>Th Levels

 $\frac{E(level)}{0.0} \quad \frac{J^{\pi}}{0^{+}}$ 

 $\alpha$  radiations

 Eα
 E(level)
  $Iα^{\ddagger}$   $HF^{\dagger}$  Comments

 8612 9
 0.0
 100
 1.000
 Eα: from 2005Le42 and 2007Le14. Other: 8625 25 (1992An04).

 Iα: No α to  $2^+$  was observed.

 $<sup>^{\</sup>dagger}$  r<sub>0</sub>( $^{214}$ Th)=1.512 *17* is calculated from HF(8612 $\alpha$ )=1.0.

<sup>&</sup>lt;sup>‡</sup> Absolute intensity per 100 decays.